

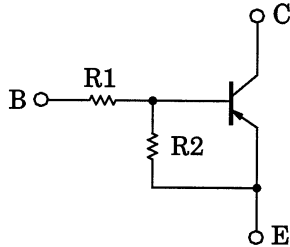
TOSHIBA Transistor Silicon PNP Epitaxial Type (PCT Process)

RN2907, RN2908, RN2909

Switching, Inverter Circuit, Interface Circuit
And Driver Circuit Applications

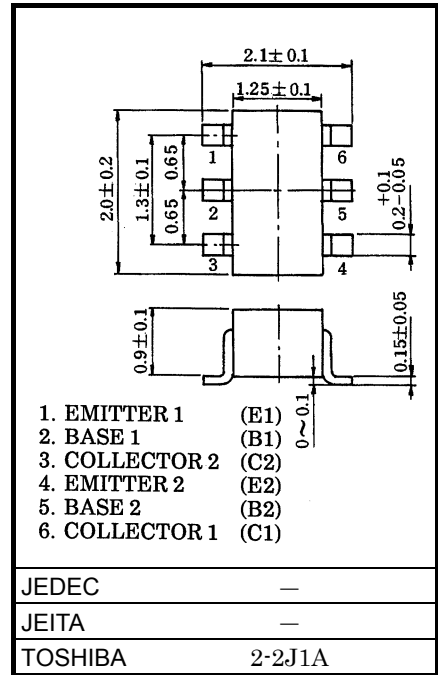
- Including two devices in US6 (ultra super mini type with 6 leads)
- With built-in bias resistors
- Simplify circuit design
- Reduce a quantity of parts and manufacturing process
- Complementary to RN1907~1909

Equivalent Circuit and Bias Resistor Values



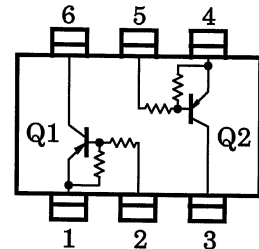
Type No.	R1 (kΩ)	R2 (kΩ)
RN2907	10	47
RN2908	22	47
RN2909	47	22

Unit in mm



Weight: 6.8 mg(typ.)

Equivalent Circuit (Top View)



Absolute Maximum Ratings (Ta = 25°C) (Q1, Q2 Common)

Characteristic		Symbol	Rating	Unit
Collector-base voltage	RN2907~2909	V_{CB0}	-50	V
Collector-emitter voltage		V_{CEO}	-50	V
Emitter-base voltage	RN2907	V_{EBO}	-6	V
	RN2908		-7	
	RN2909		-15	
Collector current	RN2907~2909	I_C	-100	mA
Collector power dissipation		P_C^*	200	mW
Junction temperature		T_j	150	°C
Storage temperature range		T_{stg}	-55~150	°C

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

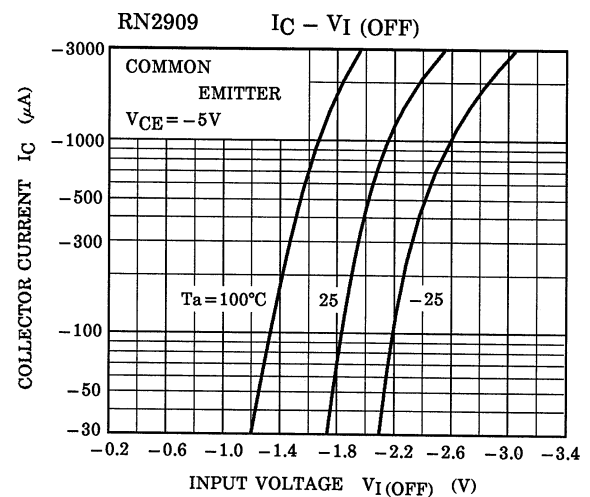
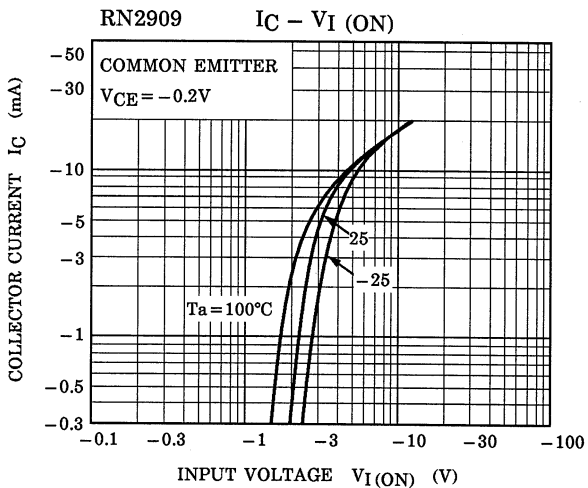
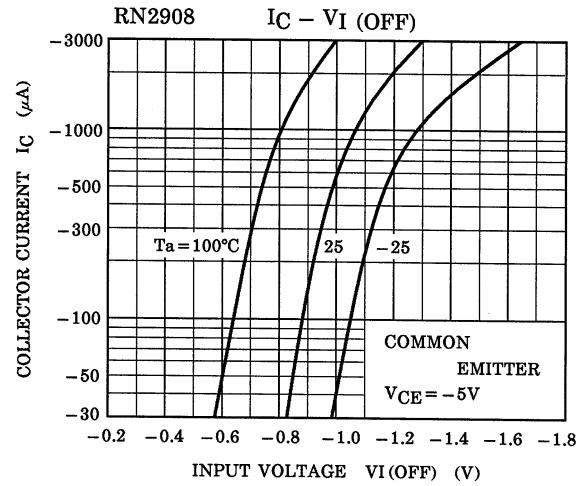
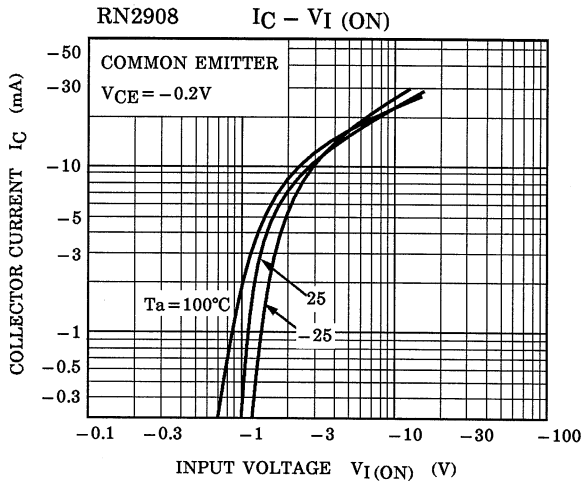
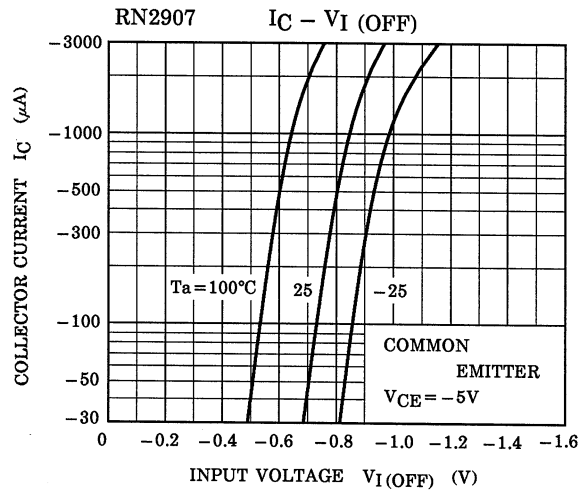
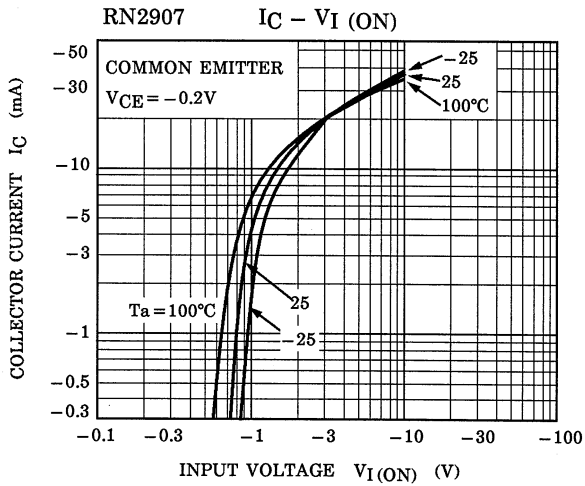
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

* : Total rating

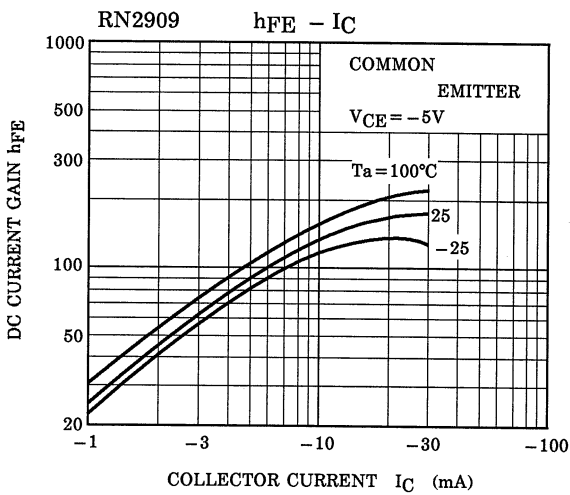
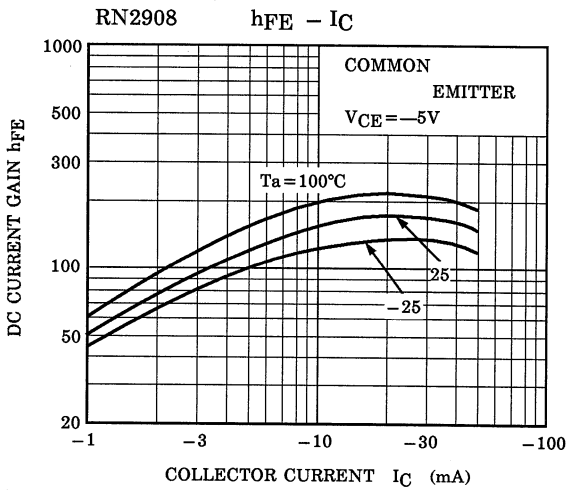
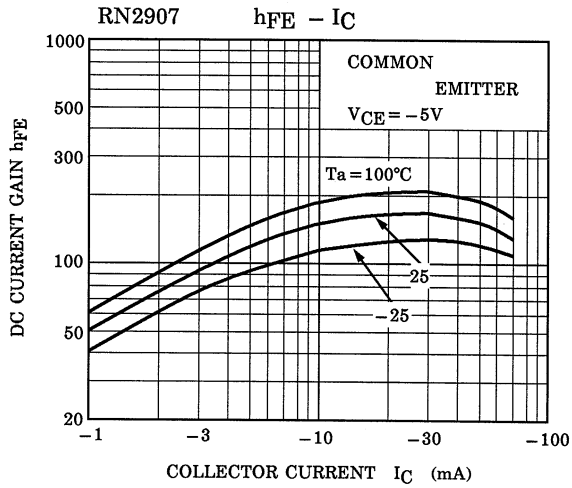
Electrical Characteristics (Ta = 25°C) (Q1, Q2 Common)

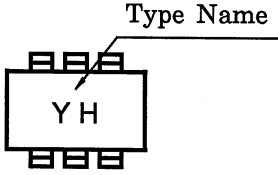
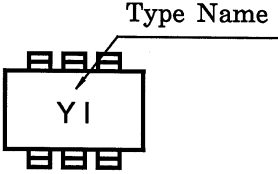
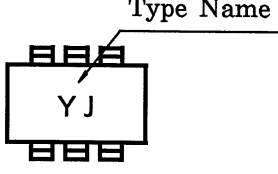
Characteristic		Symbol	Test Circuit	Test Condition	Min	Typ.	Max	Unit
Collector cut-off current	RN2907~2909	I_{CBO}	—	$V_{CB} = -50V, I_E = 0$	—	—	-100	nA
		I_{CEO}	—	$V_{CE} = -50V, I_B = 0$	—	—	-500	nA
Emitter cut-off current	RN2907	I_{EBO}	—	$V_{EB} = -6V, I_C = 0$	-0.081	—	-0.15	mA
	RN2908		—	$V_{EB} = -7V, I_C = 0$	-0.078	—	-0.145	
	RN2909		—	$V_{EB} = -15V, I_C = 0$	-0.167	—	-0.311	
DC current gain	RN2907	h_{FE}	—	$V_{CE} = -5V, I_C = -10mA$	80	—	—	—
	RN2908		—					
	RN2909		—					
Collector-emitter saturation voltage	RN2907~2909	$V_{CE(sat)}$	—	$I_C = -5mA, I_B = -0.25mA$	—	-0.1	-0.3	V
Input voltage (ON)	RN2907	$V_I(ON)$	—	$V_{CE} = -0.2V, I_C = -5mA$	-0.7	—	-1.8	V
	RN2908		—		-1.0	—	-2.6	
	RN2909		—		-2.2	—	-5.8	
Input voltage (OFF)	RN2907	$V_I(OFF)$	—	$V_{CE} = -5V, I_C = -0.1mA$	-0.5	—	-1.0	V
	RN2908		—		-0.6	—	-1.16	
	RN2909		—		-1.5	—	-2.6	
Translation frequency	RN2907~2909	f_T	—	$V_{CE} = -10V, I_C = -5mA$	—	200	—	MHz
Collector output capacitance	RN2907~2909	C_{ob}	—	$V_{CB} = -10V, I_E = 0, f = 1MHz$	—	3	6	pF
Input resistor	RN2907	R1	—	—	7	10	13	kΩ
	RN2908		—		15.4	22	28.6	
	RN2909		—		32.9	47	61.1	
Resistor ratio	RN2907	R1/R2	—	—	0.191	0.213	0.232	—
	RN2908		—		0.421	0.468	0.515	
	RN2909		—		1.92	2.14	2.35	

(Q1, Q2 Common)



(Q1, Q2 Common)



Type Name	Marking
RN2907	
RN2908	
RN2909	

RESTRICTIONS ON PRODUCT USE

20070701-EN GENERAL

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